

**Notice of References Cited**

Application/Control No.

09/706,274

Applicant(s)/Patent Under Reexam

Arney et al.

Examiner

Arlen Soderquist

Art Unit

1743

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**U.S. PATENT DOCUMENTS**

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V	Lowry, R. K. NSB Special Publication 1982, 400-72, 64-75.
W	Iannuzzi, M. Proceedings - Electronic Components Conference 1983, 33rd, 591-601.
X	Lin, A. W. et al, Proceedings - Electronic Components & Technology Conference 1991, 41st, 820-826.

<sup>\*</sup> A copy of this reference is not being furnished with this Office action. See-MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.

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W	Enlow, L. R. et al, SPIE1997, 3235, 314-321.
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<sup>1</sup> A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).<sup>1</sup> Dates in MM-YYYY format are publication dates.<sup>2</sup> Classifications may be U.S. or foreign.